TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

2SK3438

DC-DC Converter, Relay Drive and Motor Drive Applications

• Low drain-source ON resistance: RDS (ON) = 0.74Ω (typ.)

• High forward transfer admittance: $|Y_{fs}| = 4.5 \text{ S (typ.)}$

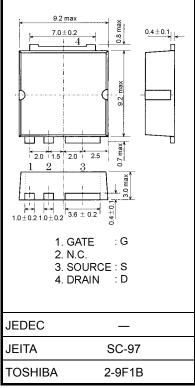
• Low leakage current: $I_{DSS} = 100 \mu A \text{ (max) (V}_{DS} = 600 \text{ V)}$

• Enhancement mode: $V_{th} = 3.0 \sim 5.0 \text{ V (VDS} = 10 \text{ V, ID} = 1 \text{ mA)}$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	600	V
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)		V_{DGR}	600	V
Gate-source voltage		V_{GSS}	±30	V
Drain current	DC (Note 1)	ΙD	10	
	Pulse (Note 1)	I _{DP}	30	Α
Drain power dissipation (Tc = 25°C)		P _D	80	W
Single pulse avalanche energy (Note 2)		E _{AS}	252	mJ
Avalanche current		I _{AR}	10	Α
Repetitive avalanche energy (Note 3)		E _{AR}	8	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C

Unit: mm



Weight: 0.74 a (tvp.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

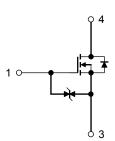
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	1.56	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: $V_{DD} = 90 \text{ V}$, $T_{ch} = 25^{\circ}\text{C}$ (initial), L = 4.41 mH, $R_G = 25 \Omega$, $I_{AR} = 10 \text{ A}$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.





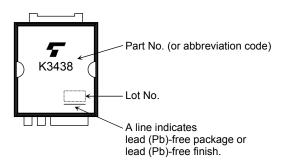
Electrical Characteristics (Ta = 25°C)

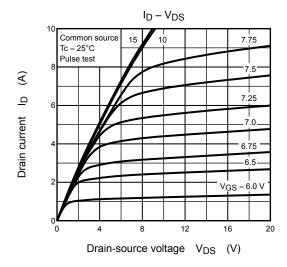
Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I _{GSS}	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Drain-source brea	akdown voltage	V (BR) GSS	$I_G = \pm 10 \ \mu A, \ V_{DS} = 0 \ V$	±30	_	_	V
Drain cut-OFF cu	rrent	I _{DSS}	V _{DS} = 600 V, V _{GS} = 0 V	_	_	100	μА
Drain-source brea	akdown voltage	V (BR) DSS	$I_D = 10$ mA, $V_{GS} = 0$ V	600	_	_	V
Gate threshold vo	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	3.0	_	5.0	V
Drain-source ON	resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 5 A	_	0.74	1.0	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 15 V, I _D = 5 A	2.0	4.5	_	S
Input capacitance)	C _{iss}		_	1200	_	
Reverse transfer capacitance		C _{rss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz	_	10	_	pF
Output capacitance		C _{oss}		_	130	_	
Switching time	Rise time	t _r	$\begin{array}{c c} 10 \text{ V} & \text{I}_D = 5 \text{ A} & \text{V}_{OUT} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline 0 \text{ V} & \text{Q} & \text{Q} \\ \hline$	_	13	_	- ns
	Turn-ON time	t _{on}		_	40		
	Fall time	t _f		_	8		
	Turn-OFF time	t _{off}		_	50	_	
Total gate charge (gate-source plus gate-drain)		Qg		_	28	_	nC
Gate-source charge		Q _{gs}	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 10 \text{ A}$	_	16	_	
Gate-drain ("miller") charge		Q _{gd}		_	12	_	

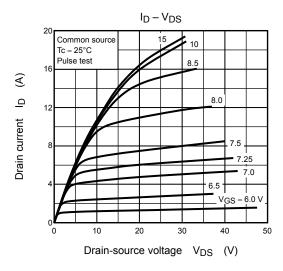
Source-Drain Ratings and Characteristics (Ta = 25°C)

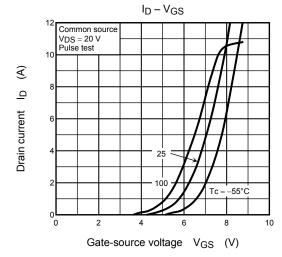
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I_{DR}	_	_	_	10	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	30	Α
Forward voltage (diode)	V_{DSF}	I _{DR} = 10 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	$I_{DR} = 10 \text{ A}, V_{GS} = 0 \text{ V},$	_	1600	_	ns
Reverse recovery charge	Q _{rr}	dI _{DR} /dt = 100 A/μs		17	_	μС

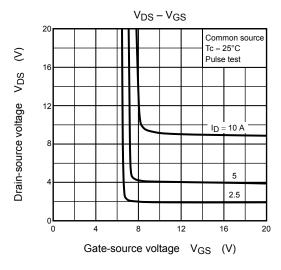
Marking

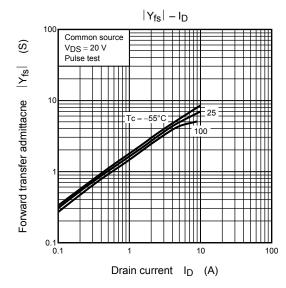


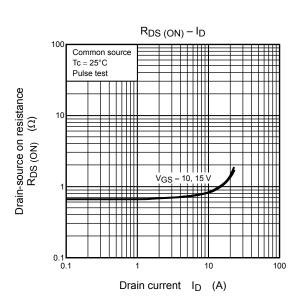




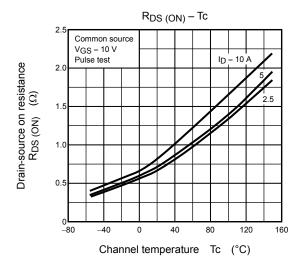


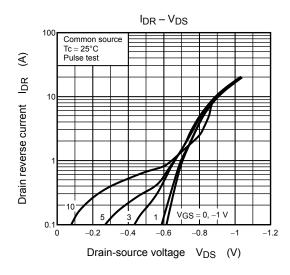


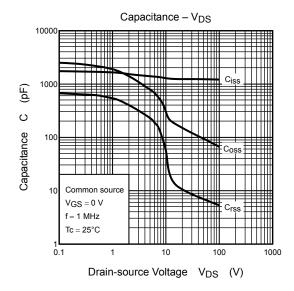


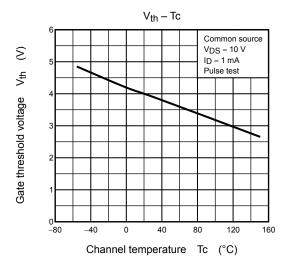


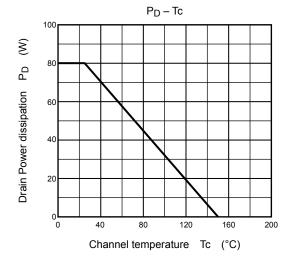
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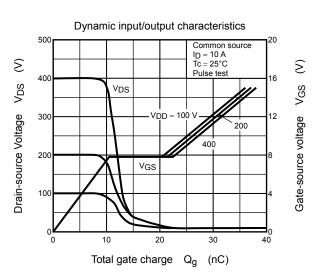


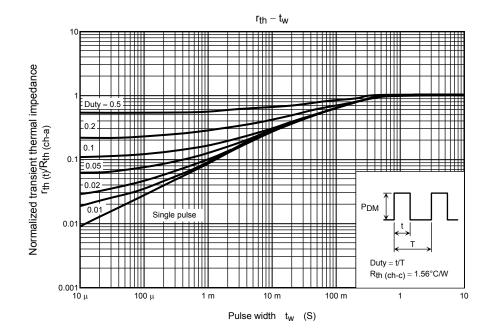


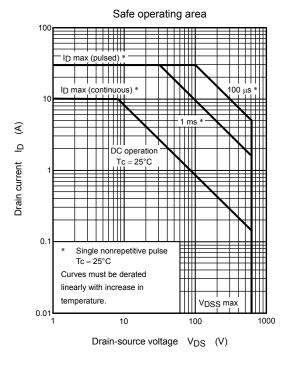


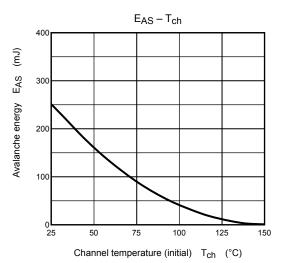


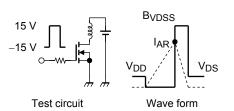












$$\begin{aligned} R_G &= 25 \ \Omega \\ V_{DD} &= 90 \ \text{V, L} = 4.41 \ \text{mH} \end{aligned} \qquad \text{EAS} = \frac{1}{2} \cdot \text{L} \cdot \text{I}^2 \cdot \left(\frac{\text{BVDSS}}{\text{BVDSS} - \text{VDD}} \right)$$

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